What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	XCore
Core Size	32-Bit 12-Core
Speed	800MIPS
Connectivity	Configurable
Peripherals	-
Number of I/O	84
Program Memory Size	128KB (32K x 32)
Program Memory Type	SRAM
EEPROM Size	-
RAM Size	-
Voltage - Supply (Vcc/Vdd)	0.95V ~ 3.6V
Data Converters	-
Oscillator Type	External
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	124-TFQFN Dual Rows, Exposed Pad
Supplier Device Package	124-QFN DualRow (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/xmos/xs1-l12a-128-qf124-c8

- **Channels and channel ends** Tasks running on logical cores communicate using channels formed between two channel ends. Data can be passed synchronously or asynchronously between the channel ends assigned to the communicating tasks. Section 5.5
- **xCONNECT Switch and Links** Between tiles, channel communications are implemented over a high performance network of xCONNECT Links and routed through a hardware xCONNECT Switch. Section 5.6
- **Ports** The I/O pins are connected to the processing cores by Hardware Response ports. The port logic can drive its pins high and low, or it can sample the value on its pins optionally waiting for a particular condition. Section 5.3
- **Clock blocks** xCORE devices include a set of programmable clock blocks that can be used to govern the rate at which ports execute. Section 5.4
- **Memory** Each xCORE Tile integrates a bank of SRAM for instructions and data, and a block of one-time programmable (OTP) memory that can be configured for system wide security features. Section 8
- **PLL** The PLL is used to create a high-speed processor clock given a low speed external oscillator. Section 6
- **JTAG** The JTAG module can be used for loading programs, boundary scan testing, in-circuit source-level debugging and programming the OTP memory. Section 9

1.1 Software

Devices are programmed using C, C++ or xC (C with multicore extensions). XMOS provides tested and proven software libraries, which allow you to quickly add interface and processor functionality such as USB, Ethernet, PWM, graphics driver, and audio EQ to your applications.

1.2 xTIMEcomposer Studio

The xTIMEcomposer Studio development environment provides all the tools you need to write and debug your programs, profile your application, and write images into flash memory or OTP memory on the device. Because xCORE devices operate deterministically, they can be simulated like hardware within xTIMEcomposer: uniquely in the embedded world, xTIMEcomposer Studio therefore includes a static timing analyzer, cycle-accurate simulator, and high-speed in-circuit instrumentation.

xTIMEcomposer can be driven from either a graphical development environment, or the command line. The tools are supported on Windows, Linux and MacOS X and available at no cost from xmos.com/downloads. Information on using the tools is provided in the xTIMEcomposer User Guide, X3766.

2 XS1-L12A-128-QF124 Features

- **Multicore Microcontroller with Advanced Multi-Core RISC Architecture**
  - 12 real-time logical cores on 2 xCORE tiles
  - Cores share up to 500 MIPS
  - Each logical core has:
    - Guaranteed throughput of between 1/4 and 1/6 of tile MIPS
    - 16x32bit dedicated registers
  - 159 high-density 16/32-bit instructions
    - All have single clock-cycle execution (except for divide)
    - 32x32→64-bit MAC instructions for DSP, arithmetic and user-definable cryptographic functions
- **Programmable I/O**
  - 28 general-purpose I/O pins, configurable as input or output
    - Up to 32 x 1bit port, 12 x 4bit port, 7 x 8bit port, 3 x 16bit port
    - 4 xCONNECT links
  - Port sampling rates of up to 60 MHz with respect to an external clock
  - 64 channel ends for communication with other cores, on or off-chip
- **Memory**
  - 128KB internal single-cycle SRAM (max 64KB per tile) for code and data storage
  - 8KB internal OTP (max 8KB per tile) for application boot code
- **Hardware resources**
  - 12 clock blocks (6 per tile)
  - 20 timers (10 per tile)
  - 8 locks (4 per tile)
- **JTAG Module for On-Chip Debug**
- **Security Features**
  - Programming lock disables debug and prevents read-back of memory contents
  - AES bootloader ensures secrecy of IP held on external flash memory
- **Ambient Temperature Range**
  - Commercial qualification: 0 °C to 70 °C
  - Industrial qualification: -40 °C to 85 °C
- **Speed Grade**
  - 10: 1000 MIPS
  - 8: 800 MIPS
- **Power Consumption**
  - Active Mode
    - 400 mA at 500 MHz (typical)
    - 320 mA at 400 MHz (typical)
  - Standby Mode
    - 28 mA
- **124-pin QF124 package 0.5 mm pitch**

The JTAG usercode register can be read by using the USERCODE instruction. Its contents are specified in Figure 13. The OTP User ID field is read from bits [22:31] of the security register on xCORE Tile 0, *see* §8.1 (all zero on unprogrammed devices).

Figure 13: USERCODE return value

<table>
<tr><td colspan="4">Bit31</td><td colspan="24">Usercode Register</td><td colspan="4">Bit0</td></tr>
<tr><td colspan="10">OTP User ID</td><td colspan="4">Unused</td><td colspan="18">Silicon Revision</td></tr>
<tr><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>1</td><td>0</td><td>1</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td><td>0</td></tr>
<tr><td colspan="4">0</td><td colspan="4">0</td><td colspan="4">0</td><td colspan="4">2</td><td colspan="4">8</td><td colspan="4">0</td><td colspan="4">0</td><td colspan="4">0</td></tr>
</table>

9.1 PCU

PCU_WAKE should be left unconnected, PCU_GATE should be left unconnected and PCU_CLK must be tied to CLK.

10 Board Integration

The device has the following power supply pins:

- VDD pins for the xCORE Tile
- VDDIO pins for the I/O lines
- PLL_AVDD pins for the PLL
- PCU_VDD and PCU_VDDIO pins for the PCU
- OTP_VCC pins for the OTP

Several pins of each type are provided to minimize the effect of inductance within the package, all of which must be connected. The power supplies must be brought up monotonically and input voltages must not exceed specification at any time.

The VDD supply must ramp from 0 V to its final value within 10 ms to ensure correct startup.

The VDDIO and OTP_VCC supply must ramp to its final value before VDD reaches 0.4 V.

The PLL_AVDD supply should be separated from the other noisier supplies on the board. The PLL requires a very clean power supply, and a low pass filter (for example, a 2.2 Ω resistor and 100 nF multi-layer ceramic capacitor) is recommended on this pin.

The PCU_VDD supply must be connected to the VDD supply.

The PCU_VDDIO supply must be connected to the VDDIO supply.

The OTP_VCC supply should be connected to the VDDIO supply.

The following ground pins are provided:

- PLL_AGND for PLL_AVDD
- GND for all other supplies

All ground pins must be connected directly to the board ground.

The VDD and VDDIO supplies should be decoupled close to the chip by several 100 nF low inductance multi-layer ceramic capacitors between the supplies and GND (for example, 4x100nF 0402 low inductance MLCCs per supply rail). The ground side of the decoupling capacitors should have as short a path back to the GND pins as possible. A bulk decoupling capacitor of at least 10 uF should be placed on each of these supplies.

RST_N is an active-low asynchronous-assertion global reset signal. Following a reset, the PLL re-establishes lock after which the device boots up according to the boot mode (*see* §7). RST_N and must be asserted low during and after power up for 100 ns.

10.1 Land patterns and solder stencils

The land pattern recommendations in this document are based on a RoHS compliant process and derived, where possible, from the nominal *Generic Requirements for Surface Mount Design and Land Pattern Standards* IPC-7351B specifications. This standard aims to achieve desired targets of heel, toe and side fillets for solder-joints.

Solder paste and ground via recommendations are based on our engineering and development kit board production. They have been found to work and optimized as appropriate to achieve a high yield. The size, type and number of vias used in the center pad affects how much solder wicks down the vias during reflow. This in turn, along with solder paster coverage, affects the final assembled package height. These factors should be taken into account during design and manufacturing of the PCB.

The following land patterns and solder paste contains recommendations. Final land pattern and solder paste decisions are the responsibility of the customer. These should be tuned during manufacture to suit the manufacturing process.

The package is a 124 pin dual row Quad Flat No lead package with exposed heat slug on a 0.5mm pitch. An example land pattern is shown in Figure 14.

Pad widths and spacings are such that solder mask can still be applied between the pads using standard design rules. This is highly recommended to reduce solder shorts between pads. See the recommended PCB solder mask diagram in Figure 15.

10.2 Solder Stencil

The solder joints in the QFN package are formed exclusively from the solder paste deposited from the solder stencil. At the small aperture sizes required, the design of the stencil becomes important to ensure a reliable final solder joint volume and reliable solder joints.

11 DC and Switching Characteristics

11.1 Operating Conditions

Figure 18: Operating conditions

Symbol	Parameter	MIN	TYP	MAX	UNITS	Notes
VDD	Tile DC supply voltage	0.95	1.00	1.05	V	
VDDIO	I/O supply voltage	3.00	3.30	3.60	V	
PLL_AVDD	PLL analog supply	0.95	1.00	1.05	V	
PCU_VDD	PCU tile DC supply voltage	0.95	1.00	1.05	V	
PCU_VDDIO	PCU I/O DC supply voltage	3.00	3.30	3.60	V	
OTP_VCC	OTP supply voltage	3.00	3.30	3.60	V	
Cl	xCORE Tile I/O load capacitance			25	pF	
Ta	Ambient operating temperature (Commercial)	0		70	°C	
	Ambient operating temperature (Industrial)	-40		85	°C	
Tj	Junction temperature			125	°C	
Tstg	Storage temperature	-65		150	°C	

11.2 DC Characteristics

Figure 19: DC characteristics

Symbol	Parameter	MIN	TYP	MAX	UNITS	Notes
V(IH)	Input high voltage	2.00		3.60	V	A
V(IL)	Input low voltage	-0.30		0.70	V	A
V(OH)	Output high voltage	2.00			V	B, C
V(OL)	Output low voltage			0.60	V	B, C
R(PU)	Pull-up resistance		35K		Ω	D
R(PD)	Pull-down resistance		35K		Ω	D

A All pins except power supply pins.

B Ports 1A, 1D, 1E, 1H, 1I, 1J, 1K and 1L are nominal 8 mA drivers, the remainder of the general-purpose I/Os are 4 mA.

C Measured with 4 mA drivers sourcing 4 mA, 8 mA drivers sourcing 8 mA.

D Used to guarantee logic state for an I/O when high impedance. The internal pull-ups/pull-downs should not be used to pull external circuitry.

11.3 ESD Stress Voltage

Figure 20: ESD stress voltage

Symbol	Parameter	MIN	TYP	MAX	UNITS	Notes
HBM	Human body model	-2.00		2.00	KV	
MM	Machine model	-200		200	V	

11.4 Reset Timing

Figure 21: Reset timing

Symbol	Parameters	MIN	TYP	MAX	UNITS	Notes
T(RST)	Reset pulse width	5			us	
T(INIT)	Initialization time			150	µs	A

A Shows the time taken to start booting after RST_N has gone high.

11.5 Power Consumption

Figure 22: xCORE Tile currents

Symbol	Parameter	MIN	TYP	MAX	UNITS	Notes
I(DDCQ)	Quiescent VDD current		28		mA	A, B, C
PD	Tile power dissipation		450		µW/MIPS	A, D, E, F
IDD	Active VDD current (Speed Grade 8)		320	600	mA	A, G
	Active VDD current (Speed Grade 10)		400	750	mA	A, H
I(ADDPLL)	PLL_AVDD current			14	mA	I

A Use for budgetary purposes only.

B Assumes typical tile and I/O voltages with no switching activity.

C Includes PLL current.

D Assumes typical tile and I/O voltages with nominal switching activity.

E Assumes 1 MHz = 1 MIPS.

F PD(TYP) value is the usage power consumption under typical operating conditions.

G Measurement conditions: VDD = 1.0 V, VDDIO = 3.3 V, 25 °C, 400 MHz, average device resource usage.

H Measurement conditions: VDD = 1.0 V, VDDIO = 3.3 V, 25 °C, 500 MHz, average device resource usage.

I PLL_AVDD = 1.0 V

⚠ The tile power consumption of the device is highly application dependent and should be used for budgetary purposes only.

More detailed power analysis can be found in the XS1-L Power Consumption document, X2999.

The asynchronous nature of links means that the relative phasing of CLK clocks is not important in a multi-clock system, providing each meets the required stability criteria.

11.9 JTAG Timing

Figure 26: JTAG timing

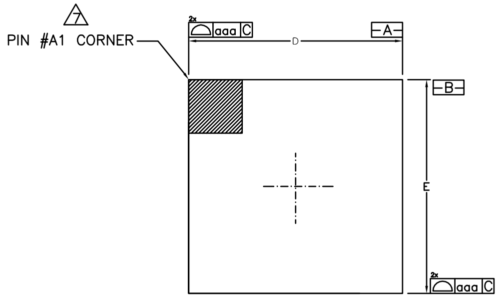
Symbol	Parameter	MIN	TYP	MAX	UNITS	Notes
f(TCK_D)	TCK frequency (debug)			18	MHz	
f(TCK_B)	TCK frequency (boundary scan)			10	MHz	
T(SETUP)	TDO to TCK setup time	5			ns	A
T(HOLD)	TDO to TCK hold time	5			ns	A
T(DELAY)	TCK to output delay			15	ns	B

A Timing applies to TMS and TDI inputs.

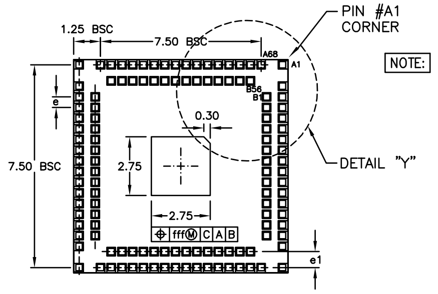
B Timing applies to TDO output from negative edge of TCK.

All JTAG operations are synchronous to TCK apart from the global asynchronous reset TRST_N.

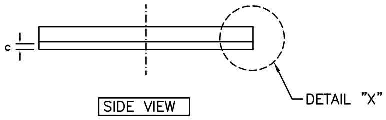
12 Package Information



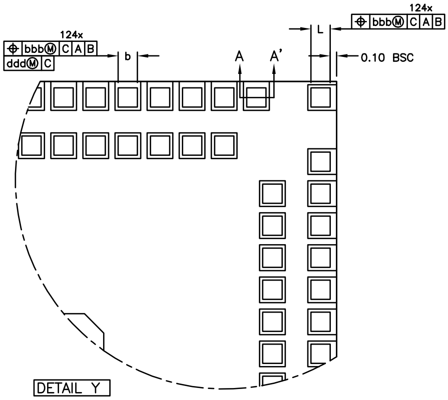
TOP VIEW



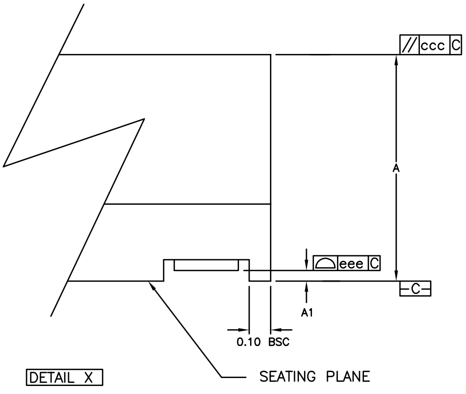
BOTTOM VIEW



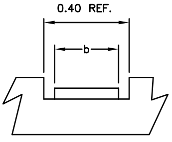
SIDE VIEW



DETAIL Y



DETAIL X



A–A'

SYMBOL	MIN.	NOM.	MAX.
A	1.01	1.06	1.11
A1	0.00	–	0.05
D	9.90	10.00	10.10
E	9.90	10.00	10.10
aaa			0.10
bbb			0.10
ccc			0.10
ddd			0.08
eee			0.08
fff			0.10
b	0.25	0.30	0.35
L	0.25	0.30	0.35
e	0.50 BSC.		
e1	0.75 BSC.		
c	0.36 REF.		

1. ALL DIMENSIONS ARE IN MILLIMETERS.
2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M–1994
3. PRIMARY DATUM -C- AND SEATING PLANE ARE DESIGNED BY THE SPHERICAL CROWNS OF THE SOLDER BALLS.
4. A1 CORNER MUST BE IDENTIFIED BY INK OR LASER MARK.

Appendices

A Configuration of the XS1

The device is configured through three banks of registers, as shown in Figure 29.

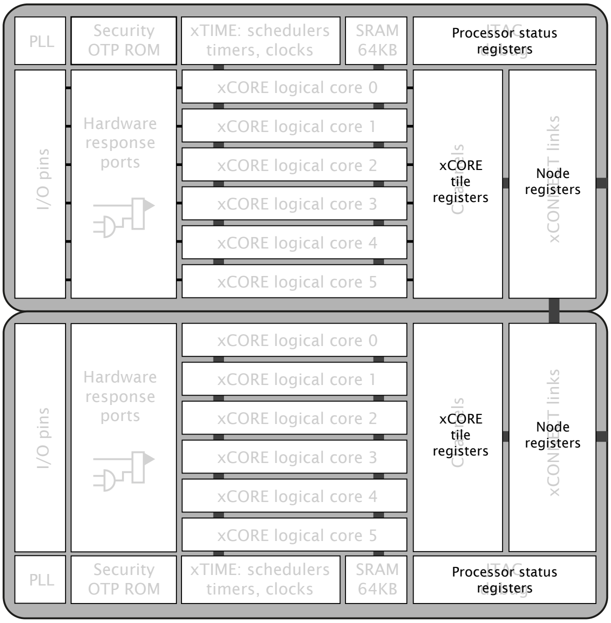


Figure 29: Registers

The following communication sequences specify how to access those registers. Any messages transmitted contain the most significant 24 bits of the channel-end to which a response is to be sent. This comprises the node-identifier and the channel number within the node. if no response is required on a write operation, supply 24-bits with the last 8-bits set, which suppresses the reply message. Any multi-byte data is sent most significant byte first.

A.1 Accessing a processor status register

The processor status registers are accessed directly from the processor instruction set. The instructions GETPS and SETPS read and write a word. The register number should be translated into a processor-status resource identifier by shifting the register number left 8 places, and ORing it with 0x0C. Alternatively, the functions `getps(reg)` and `setps(reg,value)` can be used from XC.

A.2 Accessing an xCORE Tile configuration register

xCORE Tile configuration registers can be accessed through the interconnect using the functions `write_tile_config_reg(tileref, ...)` and `read_tile_config_reg(tile`

0x03: xCORE Tile boot status

Bits	Perm	Init	Description
31:24	RO	-	Reserved
23:16	RO		xCORE tile number on the switch.
15:9	RO	-	Reserved
8	RO		Set to 1 if boot from OTP is enabled.
7:0	RO		The boot mode pins MODE0, MODE1, ..., specifying the boot frequency, boot source, etc.

B.5 Security configuration: 0x05

Copy of the security register as read from OTP.

0x05: Security configuration

Bits	Perm	Init	Description
31:0	RO		Value.

B.6 Ring Oscillator Control: 0x06

There are four free-running oscillators that clock four counters. The oscillators can be started and stopped using this register. The counters should only be read when the ring oscillator is stopped. The counter values can be read using four subsequent registers. The ring oscillators are asynchronous to the xCORE tile clock and can be used as a source of random bits.

0x06: Ring Oscillator Control

Bits	Perm	Init	Description
31:2	RO	-	Reserved
1	RW	0	Set to 1 to enable the xCORE tile ring oscillators
0	RW	0	Set to 1 to enable the peripheral ring oscillators

B.7 Ring Oscillator Value: 0x07

This register contains the current count of the xCORE Tile Cell ring oscillator. This value is not reset on a system reset.

0x07: Ring Oscillator Value

Bits	Perm	Init	Description
31:16	RO	-	Reserved
15:0	RO	-	Ring oscillator counter data.

0x11: Debug SPC

Bits	Perm	Init	Description
31:0	DRW		Value.

B.13 Debug SSP: 0x12

This register contains the value of the SSP register when the debugger was called.

0x12: Debug SSP

Bits	Perm	Init	Description
31:0	DRW		Value.

B.14 DGETREG operand 1: 0x13

The resource ID of the logical core whose state is to be read.

0x13: DGETREG operand 1

Bits	Perm	Init	Description
31:8	RO	-	Reserved
7:0	DRW		Thread number to be read

B.15 DGETREG operand 2: 0x14

Register number to be read by DGETREG

0x14: DGETREG operand 2

Bits	Perm	Init	Description
31:5	RO	-	Reserved
4:0	DRW		Register number to be read

B.16 Debug interrupt type: 0x15

Register that specifies what activated the debug interrupt.

B.19 Debug scratch: 0x20 .. 0x27

A set of registers used by the debug ROM to communicate with an external debugger, for example over JTAG. This is the same set of registers as the Debug Scratch registers in the xCORE tile configuration.

0x20 .. 0x27: Debug scratch

Bits	Perm	Init	Description
31:0	DRW		Value.

B.20 Instruction breakpoint address: 0x30 .. 0x33

This register contains the address of the instruction breakpoint. If the PC matches this address, then a debug interrupt will be taken. There are four instruction breakpoints that are controlled individually.

0x30 .. 0x33: Instruction breakpoint address

Bits	Perm	Init	Description
31:0	DRW		Value.

B.21 Instruction breakpoint control: 0x40 .. 0x43

This register controls which logical cores may take an instruction breakpoint, and under which condition.

0x40 .. 0x43: Instruction breakpoint control

Bits	Perm	Init	Description
31:24	RO	-	Reserved
23:16	DRW	0	A bit for each logical core in the tile allowing the breakpoint to be enabled individually for each logical core.
15:2	RO	-	Reserved
1	DRW	0	Set to 1 to cause an instruction breakpoint if the PC is not equal to the breakpoint address. By default, the breakpoint is triggered when the PC is equal to the breakpoint address.
0	DRW	0	When 1 the instruction breakpoint is enabled.

B.22 Data watchpoint address 1: 0x50 .. 0x53

This set of registers contains the first address for the four data watchpoints.

0x50 .. 0x53: Data watchpoint address 1

Bits	Perm	Init	Description
31:0	DRW		Value.

B.23 Data watchpoint address 2: 0x60 .. 0x63

This set of registers contains the second address for the four data watchpoints.

0x60 .. 0x63: Data watchpoint address 2

Bits	Perm	Init	Description
31:0	DRW		Value.

B.24 Data breakpoint control register: 0x70 .. 0x73

This set of registers controls each of the four data watchpoints.

0x70 .. 0x73: Data breakpoint control register

Bits	Perm	Init	Description
31:24	RO	-	Reserved
23:16	DRW	0	A bit for each logical core in the tile allowing the breakpoint to be enabled individually for each logical core.
15:3	RO	-	Reserved
2	DRW	0	Set to 1 to enable breakpoints to be triggered on loads. Breakpoints always trigger on stores.
1	DRW	0	By default, data watchpoints trigger if memory in the range [Address1..Address2] is accessed (the range is inclusive of Address1 and Address2). If set to 1, data watchpoints trigger if memory outside the range (Address2..Address1) is accessed (the range is exclusive of Address2 and Address1).
0	DRW	0	When 1 the instruction breakpoint is enabled.

B.25 Resources breakpoint mask: 0x80 .. 0x83

This set of registers contains the mask for the four resource watchpoints.

0x04: Control PSwitch permissions to debug registers

Bits	Perm	Init	Description
31:1	RO	-	Reserved
0	CRW		Set to 1 to restrict PSwitch access to all CRW marked registers to become read-only rather than read-write.

C.5 Cause debug interrupts: 0x05

This register can be used to raise a debug interrupt in this xCORE tile.

0x05: Cause debug interrupts

Bits	Perm	Init	Description
31:2	RO	-	Reserved
1	RO	0	Set to 1 when the processor is in debug mode.
0	CRW	0	Set to 1 to request a debug interrupt on the processor.

C.6 xCORE Tile clock divider: 0x06

This register contains the value used to divide the PLL clock to create the xCORE tile clock. The divider is enabled under control of the tile control register

0x06: xCORE Tile clock divider

Bits	Perm	Init	Description
31:8	RO	-	Reserved
7:0	RW		Value of the clock divider minus one.

C.7 Security configuration: 0x07

Copy of the security register as read from OTP.

0x07: Security configuration

Bits	Perm	Init	Description
31:0	RO		Value.

C.8 PLink status: 0x10 .. 0x13

Status of each of the four processor links; connecting the xCORE tile to the switch.

0x10 .. 0x13: PLink status

Bits	Perm	Init	Description
31:26	RO	-	Reserved
25:24	RO		00 - ChannelEnd, 01 - ERROR, 10 - PSCTL, 11 - Idle.
23:16	RO		Based on SRC_TARGET_TYPE value, it represents channelEnd ID or Idle status.
15:6	RO	-	Reserved
5:4	RO		Two-bit network identifier
3	RO	-	Reserved
2	RO		1 when the current packet is considered junk and will be thrown away.
1	RO	0	Set to 1 if the switch is routing data into the link, and if a route exists from another link.
0	RO	0	Set to 1 if the link is routing data into the switch, and if a route is created to another link on the switch.

C.9 Debug scratch: 0x20 .. 0x27

A set of registers used by the debug ROM to communicate with an external debugger, for example over the switch. This is the same set of registers as the Debug Scratch registers in the processor status.

0x20 .. 0x27: Debug scratch

Bits	Perm	Init	Description
31:0	CRW		Value.

C.10 PC of logical core 0: 0x40

Value of the PC of logical core 0.

0x40: PC of logical core 0

Bits	Perm	Init	Description
31:0	RO		Value.

E XMOS USB Interface

XMOS provides a low-level USB interface for connecting the device to a USB transceiver using the UTMI+ Low Pin Interface (ULPI). The ULPI signals must be connected to the pins named in Figure 33. Note also that some ports on the same tile are used internally and are not available for use when the USB driver is active (they are available otherwise).

Pin	Signal
X*n*D02	Unavailable when USB active
X*n*D03	
X*n*D04	
X*n*D05	
X*n*D06	
X*n*D07	
X*n*D08	
X*n*D09	

Pin	Signal
X*n*D12	ULPI_STP
X*n*D13	ULPI_NXT
X*n*D14	ULPI_DATA[0]
X*n*D15	ULPI_DATA[1]
X*n*D16	ULPI_DATA[2]
X*n*D17	ULPI_DATA[3]
X*n*D18	ULPI_DATA[4]
X*n*D19	ULPI_DATA[5]
X*n*D20	ULPI_DATA[6]
X*n*D21	ULPI_DATA[7]
X*n*D22	ULPI_DIR
X*n*D23	ULPI_CLK

Pin	Signal
X*n*D26	Unavailable when USB active
X*n*D27	
X*n*D28	
X*n*D29	
X*n*D30	
X*n*D31	
X*n*D32	
X*n*D33	
X*n*D37	Unavailable when USB active
X*n*D38	
X*n*D39	
X*n*D40	
X*n*D41	
X*n*D42	
X*n*D43	

Figure 33: ULPI signals provided by the XMOS USB driver

F Device Errata

This section describes minor operational differences from the data sheet and recommended workarounds. As device and documentation issues become known, this section will be updated the document revised.

To guarantee a logic low is seen on the pins RST_N, DEBUG_N, MODE[4:0], TRST_N, TMS, TCK and TDI, the driving circuit should present an impedance of less than 100 Ω to ground. Usually this is not a problem for CMOS drivers driving single inputs. If one or more of these inputs are placed in parallel, however, additional logic buffers may be required to guarantee correct operation.

For static inputs tied high or low, the relevant input pin should be tied directly to GND or VDDIO.

H Schematics Design Check List

☑ This section is a checklist for use by schematics designers using the XS1-L12A-128-QF124. Each of the following sections contains items to check for each design.

H.1 Power supplies

☐ VDDIO and OTP_VCC supply is within specification before the VDD (core) supply is turned on. Specifically, the VDDIO and OTP_VCC supply is within specification before VDD (core) reaches 0.4V (Section 10).

☐ The VDD (core) supply ramps monotonically (rises constantly) from 0V to its final value (0.95V - 1.05V) within 10ms (Section 10).

☐ The VDD (core) supply is capable of supplying 600mA (Section 10).

☐ PLL_AVDD is filtered with a low pass filter, for example an RC filter, see Section 10 .

☐ The PCU_VDD pin is connected to the VDD supply and PCU_VDDIO is connected to the VDDIO supply (Section 10).

H.2 Power supply decoupling

☐ The design has multiple decoupling capacitors per supply, for example at least four0402 or 0603 size surface mount capacitors of 100nF in value, per supply (Section 10).

☐ A bulk decoupling capacitor of at least 10uF is placed on each supply (Section 10).

H.3 Power on reset

☐ The RST_N and TRST_N pins are asserted (low) during or after power up. The device is not used until these resets have taken place.
As the errata in the datasheets show, the internal pull-ups on these two pins can occasionally provide stronger than normal pull-up currents. For this reason, an RC type reset circuit is discouraged as behavior would be unpredictable. A voltage supervisor type reset device is recommended to guarantee a good reset. This also has the benefit of resetting the system should the relevant supply go out of specification.

H.4 Clock

☐ The CLK input pin is supplied with a clock with monotonic rising edges and low jitter.

☐ The PCU_CLK pin is supplied with a clock, for example it is tied to the main CLK (Section 9.1).

☐ The PCU_WAKE and PCU_GATE pins should be left unconnected (Section 9.1).

☐ Pins MODE0 and MODE1 are set to the correct value for the chosen oscillator frequency. The MODE settings are shown in the Oscillator section, Section 6. If you have a choice between two values, choose the value with the highest multiplier ratio since that will boot faster.

H.5 USB ULPI Mode

This section can be skipped if you do not have an external USB PHY.

☐ If using ULPI, the ULPI signals are connected to specific ports as shown in Section E.

☐ If using ULPI, the ports that are used internally are not connected, see Section E. (Note that this limitation only applies when the ULPI is enabled, they can still be used before or after the ULPI is being used.)

H.6 Boot

☐ The device is connected to a SPI flash for booting, connected to X0D0, X0D01, X0D10, and X0D11 (Section 7). If not, you must boot the device through OTP or JTAG.

☐ The device that is connected to flash has both MODE2 and MODE3 connected to pin 3 on the xSYS Header (MSEL). If no debug adapter connection is supported (not recommended) MODE2 and MODE3 are to be left NC (Section 7). MODE4 is set in accordance with Section 7.

☐ The SPI flash that you have chosen is supported by **xflash**, or you have created a specification file for it.

H.7 JTAG, XScope, and debugging

☐ You have decided as to whether you need an XSYS header or not (Section G)

☐ If you included an XSYS header, you connected pin 3 to any MODE2/MODE3 pin that would otherwise be NC (Section G).

☐ If you have not included an XSYS header, you have devised a method to program the SPI-flash or OTP (Section G).

H.8 GPIO

☐ You have not mapped both inputs and outputs to the same multi-bit port.

H.9 Multi device designs

Skip this section if your design only includes a single XMOS device.

☐ One device is connected to a SPI flash for booting.

☐ Devices that boot from link have MODE2 grounded and MODE3 NC. These device must have link XLB connected to a device to boot from (see 7).

☐ If you included an XSYS header, you have included buffers for RST_N, TRST_N, TMS, TCK, MODE2, and MODE3 (Section F).

I PCB Layout Design Check List

☑ This section is a checklist for use by PCB designers using the XS1-L12A-128-QF124. Each of the following sections contains items to check for each design.

I.1 Land pattern and solder stencil

☐ You have used a land pattern suitable for the small QFN pads. (Section 10.1)

☐ You have used a solder stencil with the correct aperture and thinness. (Section 10.1)

I.2 Ground Plane

☐ Multiple vias (eg, 9) have been used to connect the center pad to the PCB ground plane. These minimize impedance and conduct heat away from the device. (Section 10.3).

☐ Other than ground vias, there are no (or only a few) vias underneath or closely around the device. This create a good, solid, ground plane.

I.3 Power supply decoupling

☐ The decoupling capacitors are all placed close to a supply pin (Section 10).

☐ The decoupling capacitors are spaced around the device (Section 10).

☐ The ground side of each decoupling capacitor has a direct path back to the center ground of the device.

I.4 PLL_AVDD

☐ The PLL_AVDD filter (especially the capacitor) is placed close to the PLL_AVDD pin (Section 10).